



PIT Limited

高準檢驗及檢測有限公司

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TYPE OF INSPECTION BODY

檢驗機構類別

: A : Provides 'third party' inspection service to the public 向公眾提供「第三方」檢驗服務

ACCREDITED INSPECTION

FIELD

認可檢驗領域

: Indoor Air Quality Inspection 室內空氣質素檢驗

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Indoor Air Quality Inspection 室內空氣質素檢驗

ITEM INSPECTED 檢驗項目	SPECIFIC PROPERTY OR CHARACTERISTIC INSPECTED 特定檢驗特性或特徵	SPECIFIC INSPECTION METHOD OR STANDARD 特定檢驗方法或標準
Indoor Air Quality	On-site measurement of : - Temperature - Relative Humidity - Air Movement - Carbon Dioxide - Carbon Monoxide - Respirable Suspended Particulate - Total Volatile Organic Compound - Radon - Ozone On-site sampling of : - Airborne Bacteria - Formaldehyde - Nitrogen Dioxide Walkthrough Inspection IAQ Compliance Assessment	A Guide on Indoor Air Quality Certification Scheme for Offices and Public Places, The Government of the HKSAR, Indoor Air Quality Management Group, September 2003 Annex 3 (a), as documented in SOP-202-SG (Thermistor) Annex 3 (a), as documented in SOP-202-SG (Thin-film capacitive sensor) Annex 3 (a), as documented in SOP-201-SG (Hot wire velocity probe) Annex 3 (b), as documented in SOP-202-SG (Non-dispersive infrared NDIR) Annex 3 (b), as documented in SOP-202-SG (Electrochemical sensor) Annex 3 (g), as documented in SOP-205-SG (Light scattering laser diode) Annex 3 (h), as documented in SOP-206-SG (Photo-ionization sensor) Annex 3 (c), as documented in SOP-204-SG (Electrostatic collection of alpha-emitters (Diffused junction photodiode) Annex 3 (f), as documented in SOP-203-SG (Gas sensitive semiconductor sensor) Annex 3 (i), as documented in SOP-207-SG (Single stage impactor) Annex 3 (d), as documented in SOP-208-SG (Passive sampler) Annex 3 (e), as documented in SOP-209-SG (Passive sampler) Clause 11 Clause 13 to Clause 28

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Indoor Air Quality Inspection 室內空氣質素檢驗

ITEM INSPECTED 檢驗項目	SPECIFIC PROPERTY OR CHARACTERISTIC INSPECTED 特定檢驗特性或特徵	SPECIFIC INSPECTION METHOD OR STANDARD 特定檢驗方法或標準
Indoor Air Quality Inspection	<p>On-site measurement of :</p> <ul style="list-style-type: none"> - Carbon Dioxide - Carbon Monoxide - Respirable Suspended Particulate - Total Volatile Organic Compound - Radon - Ozone - Formaldehyde - Nitrogen Dioxide <p>On-site sampling of :</p> <ul style="list-style-type: none"> - Airborne Bacteria - Formaldehyde - Nitrogen Dioxide <p>Walkthrough Inspection</p> <p>Mould Inspection</p> <p>IAQ Compliance Assessment</p>	<p>A Guide on Indoor Air Quality Certification Scheme for Offices and Public Places, The Government of the HKSAR, Indoor Air Quality Management Group, January 2019</p> <p>Annex 4 (a), as documented in SOP-202-SG (Non-dispersive infrared NDIR)</p> <p>Annex 4 (a), as documented in SOP-202-SG (Electrochemical sensor)</p> <p>Annex 4 (f), as documented in SOP-205-SG (Light scattering laser diode)</p> <p>Annex 4 (g), as documented in SOP-206-SG (Photo-ionization sensor)</p> <p>Annex 4 (b), as documented in SOP-204-SG (Electrostatic collection of alpha-emitters) (Diffused junction photodiode)</p> <p>Annex 4 (e), as documented in SOP-203-SG (Gas sensitive semiconductor sensor)</p> <p>Annex 4 (c), as documented in SOP-213-SG (Photoelectric photometry detector) (Gas sensitive electrochemical sensor)</p> <p>Annex 4 (d), as documented in SOP-214-SG (Gas sensitive electrochemical sensor)</p> <p>Annex 4 (h), as documented in SOP-207-SG (Single stage impactor)</p> <p>Annex 4 (c), as documented in SOP-212-SG (Active sampler)</p> <p>Annex 4 (c), as documented in SOP-208-SG (Passive sampler)</p> <p>Annex 4 (d), as documented in SOP-209-SG (Passive sampler)</p> <p>Clauses 13 to 14</p> <p>Clause 20</p> <p>Clauses 16 to 19 and Clause 21 to 40</p>